

Search Notes

Application/Control No.

10/644,772

Examiner

Drew E. Becker

Applicant(s)/Patent under
Reexamination

KOBAYASHI ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner
search updated		8-4-06	DEB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR